SN5412, SN54LS12 SN7412, SN74LS12

SDLS040 TRIPLE 3-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

DECEMBER 1983-REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

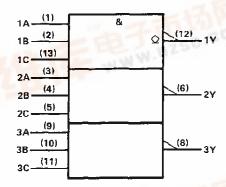
These devices contain three independent 3-input NAND gates with open-collector outputs. The open-collector outputs require pull-up resistors to perform correctly. They may be connected to other open-collector outputs to implement active-low wired-OR or active-high wired-AND functions. Open-collector devices are often used to generate higher VOH levels.

The SN5412 and SN54LS12 are characterized for operation over the full military temperature range of $-55\,^{\circ}\text{C}$ to 125 $\,^{\circ}\text{C}$. The SN7412 and SN74LS12 are characterized for operation from 0 $\,^{\circ}\text{C}$ to 70 $\,^{\circ}\text{C}$.

FUNCTION TABLE (each gate)

H	NPUT	s	OUTPUT
A	В	c	Y
Н	н	Н	L
L	Х	X	Н
х	L	x	н
Х	X	L	Н

logic symbol[†]



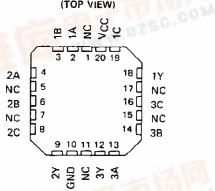
[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

SN5412, SN54LS12...J OR W PACKAGE SN7412...N PACKAGE SN74LS12...D OR N PACKAGE (TOP VIEW)

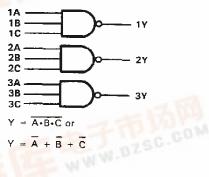
1A	1 2 3 4 5 6	14	VCC
1B		13	1C
2A		12	1Y
2B		11	3C
2C		10	3B
2Y		9	3A
GND	<u></u>	8	3Y

SN54LS12 . . . FK PACKAGE (TOP VIEW)



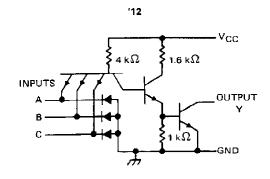
NC-No internal connection

logic diagram (positive logic)

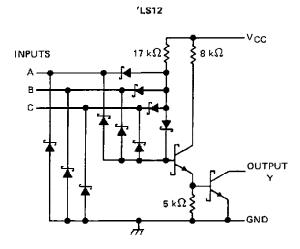


TRIPLE 3-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

schematics (each gate)



Resistor values shown are nominal.



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note	1)	7 V
Input voltage: '12	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	<i>.</i> 5.5 V
'LS12	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	7 V
Off-state output voltage		7 V
Operating free-air temperature:	SN54'	55°C to 125°C
	\$N74'	0°C to 70°C
Storage temperature range	·	–65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

SN5412, SN5412 TRIPLE 3-INPUT POSITIVE NAND GATES WITH OPEN COLLECTOR OUTPUTS

recommended operating conditions

		SN5412			SN7412			
	MIN	NOM	MAX	MIN	NOM	MAX	TINU	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5,25	V	
V _{1H} High-level input voltage	2			2		·——	V	
VIL Low-level input voltage			8.0			0.8	V	
VOH High-level output voltage			5.5			5,5	V	
IOL Low-level output current			16			16	mA	
TA Operating free-air temperature	- 55		125	0		70	∘c	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TEST CONDITIONS†	SN5412	SN7412	
PARAMETER	TEST CONDITIONS.	MIN TYP [‡] MAX	MIN TYP [‡] MAX	UNIT
VIK	VCC = MIN, II = -12 mA	-1.5	- 1.5	٧
la	V _{CC} = MIN, V _{IL} = 0.8 V, V _{OH} = 5.5 V		0.25	4
і он	$V_{CC} = MIN$, $V_{IL} = 0.7 \text{ V}$, $V_{OH} = 5.5 \text{ V}$	0.25		mA
VOL	VCC - MIN, VIH - 2 V, IOL = 16 mA	0.2 0.4	0.2 0.4	V
l _l	V _{CC} = MAX, V _I = 5.5 V	1	1	mA
IH	$V_{CC} = MAX$, $V_I = 2.4 V$	40	40	μА
lir —	$V_{CC} = MAX$, $V_I = 0.4 V$	-1.6	-1.6	mA
ССН	$V_{CC} = MAX$, $V_I = 0$	3 6	3 6	mA
CCL	VCC = MAX, VI = 4.5 V	9 16.5	9 16.5	mA

For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, VCC = 5 V, TA = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CON	TEST CONDITIONS		TYP	MAX	UNIT
^t PLH	A, B or C	Y	R <u>L</u> = 4 kΩ,	C _L = 15 pF		35	45	ns
¹₽HĻ			R _L = 400 Ω,	CL = 15 pF		8	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

 $^{^{\}ddagger}$ All typical values are at V_{CC} = 5 V, T_A = 25 °C.

SN54LS12, SN74LS12 TRIPLE 3-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

		SN54LS12			\$N74LS12			
	MIN	NOM	MAX	MIN	NOM	MAX	TINU	
V _{CC} Supply voltage	4.5	5	5,5	4.75	5	5.25	٧	
VIH High-level input voltage	2			2			٧	
VIL - Low-level input voltage			0.7			0.8	٧	
VOH High-level output voltage			5.5			5.5	٧	
IOL Low-level output current			4			. 8	mΑ	
TA Operating free-air temperature	– 55		125	0		70	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER				SN54LS	12		UNIT			
		TEST CONDITIONS †		MIN	TYP‡	MAX	MIN	TYP\$	MAX	UNII
VIK	V _{CC} = MIN,	I ₁ = 18 mA				- 1.5			- 1.5	V
^I ОН	V _{CC} = MIN,	VIL = MAX,	V _{OH} = 5.5 V			0.1			0.1	mΑ
	VCC = MIN,	V _{1H} = 2 V,	I _{OL} = 4 mA		0.25	0.4		0.25	0.4	v
VOL	V _{CC} = MIN,	V _{IH} = 2 V,	IOL = 8 mA					0.35	0.5	
11	V _{CC} = MAX,	V = 7 V				0.1			0.1	mA
ЧН	V _{CC} = MAX,	V _I = 2.7 V				20			20	μΑ
ηL	V _{CC} = MAX,	V = 0.4 V				- 0.4			- 0.4	mA
ıссн	V _{CC} = MAX,	V(= 0			- 0.7	1.4		0,7	1.4	mA
CCL	V _{CC} = MAX,	V _I = 4.5 V			1,8	3.3		1,8	3,3	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		TYP	MAX	UNIT
tPLH	A, B or C	· · · · · ·	$R_L = 2 k\Omega$, $C_L = 15 pF$		17	32	C
tPHL.	7,20.0	•	2 mas, OE (15 p)		15	28	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

[‡] All typical values are at V_{CC} = 5 V, T_A = 25°C.

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